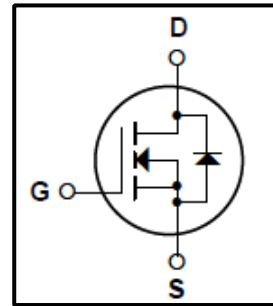


## Silicon N-Channel MOSFET

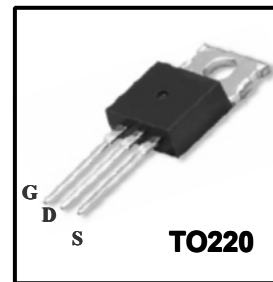
### Features

- 2A,600V,  $R_{DS(on)}$ (Max 5 $\Omega$ )@ $V_{GS}=10V$
- Ultra-low Gate Charge(Typical 9.0nC)
- Fast Switching Capability
- 100%Avalanche Tested
- Maximum Junction Temperature Range(150°C)



### General Description

This Power MOSFET is produced using Winsemi's advanced planar stripe, VDMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. This devices is specially well suited for high efficiency switch mode power supply.



### Absolute Maximum Ratings

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain Source Voltage	600	V
$I_D$	Continuous Drain Current(@ $T_c=25^\circ C$ )	2.0	A
	Continuous Drain Current(@ $T_c=100^\circ C$ )	1.3	A
$I_{DM}$	Drain Current Pulsed (Note1)	8	A
$V_{GS}$	Gate to Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	140	mJ
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	6.4	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5	V/ns
$P_D$	Total Power Dissipation(@ $T_c=25^\circ C$ )	54	W
	Derating Factor above 25°C	0.43	W/°C
$T_J, T_{stg}$	Junction and Storage Temperature	-55~150	°C
$T_L$	Maximum lead Temperature for soldering purposes	300	°C

### Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
$R_{QJC}$	Thermal Resistance, Junction-to-Case	-	-	2.3	°C/W
$R_{QCS}$	Thermal Resistance, Case-to-Sink	0.5	-	-	°C/W
$R_{QJA}$	Thermal Resistance, Junction-to-Ambient	-	-	62.5	°C/W

## Electrical Characteristics (T<sub>c</sub> = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit	
Gate leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	-	-	±100	nA	
Gate-source breakdown voltage	V <sub>(BR)GSS</sub>	I <sub>G</sub> = ±10 μA, V <sub>DS</sub> = 0 V	±30	-	-	V	
Drain cut-off current	I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	10	μA	
		V <sub>DS</sub> = 480 V, T <sub>c</sub> = 125°C	-	-	100	μA	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	600	-	-	V	
Break Voltage Temperature Coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	I <sub>D</sub> =250μA, Referenced to 25°C	-	0.5	-	V/°C	
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> =250 μA	2	-	4	V	
Drain-source ON resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> =1A	-	4.5	5	Ω	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> =1A	-	2.25	-	S	
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25 V,	-	190	230	pF	
Reverse transfer capacitance	C <sub>rss</sub>	V <sub>GS</sub> = 0 V,	-	1.8	2.1		
Output capacitance	C <sub>oss</sub>	f = 1 MHz	-	15	20		
Switching time	Rise time	t <sub>r</sub>	V <sub>DD</sub> =300 V, I <sub>D</sub> = 2 A R <sub>G</sub> =25 Ω  (Note4,5)	-	23	45	ns
	Turn-on time	t <sub>on</sub>		-	7	23	
	Fall time	t <sub>f</sub>		-	24	46	
	Turn-off time	t <sub>off</sub>		-	22	43	
Total gate charge (gate-source plus gate-drain)	Q <sub>g</sub>	V <sub>DD</sub> = 320 V, V <sub>GS</sub> = 10 V,	-	9.0	12	nC	
Gate-source charge	Q <sub>gs</sub>	I <sub>D</sub> = 2 A	-	1.7	-		
Gate-drain ("miller") Charge	Q <sub>gd</sub>	(Note4,5)	-	4.5	-		

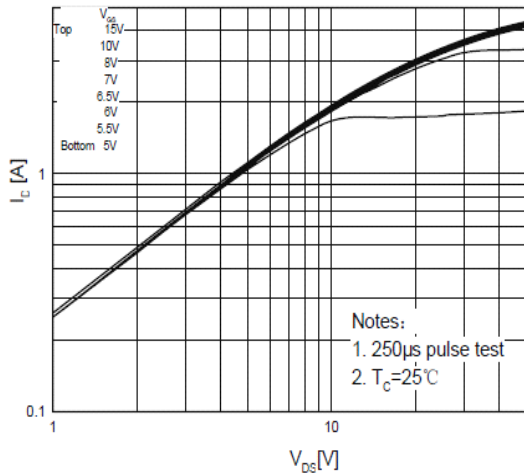
## Source-Drain Ratings and Characteristics (T<sub>a</sub> = 25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I <sub>DR</sub>	-	-	-	2	A
Pulse drain reverse current	I <sub>DRP</sub>	-	-	-	8	A
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 2 A, V <sub>GS</sub> = 0 V	-	-	1.4	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 2 A, V <sub>GS</sub> = 0 V,	-	180	-	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> / dt = 100 A / μs	-	0.72	-	μC

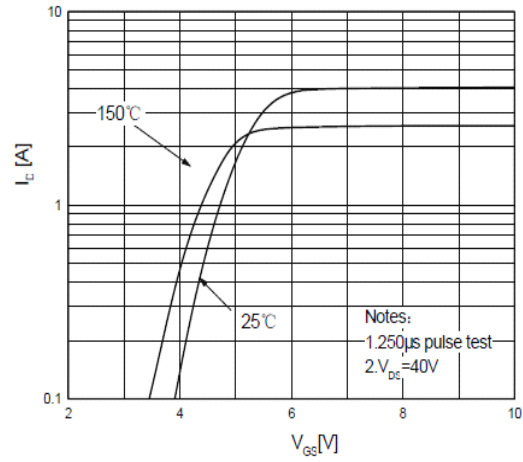
- Note 1.Repeativity rating :pulse width limited by junction temperature  
 2.L=18.5mH,I<sub>AS</sub>=2.0A,V<sub>DD</sub>=50V,R<sub>G</sub>=0Ω,Starting T<sub>J</sub>=25°C  
 3.I<sub>SD</sub>≤2.0A,di/dt≤200A/μs, V<sub>DD</sub><BV<sub>DSS</sub>,STARTING T<sub>J</sub>=25°C  
 4.Pulse Test: Pulse Width≤300us,Duty Cycle≤2%  
 5.Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

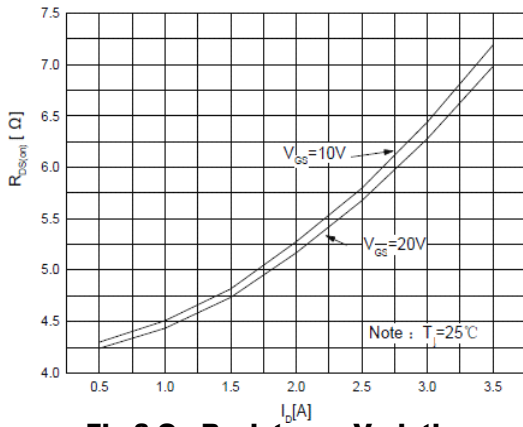
Please handle with caution



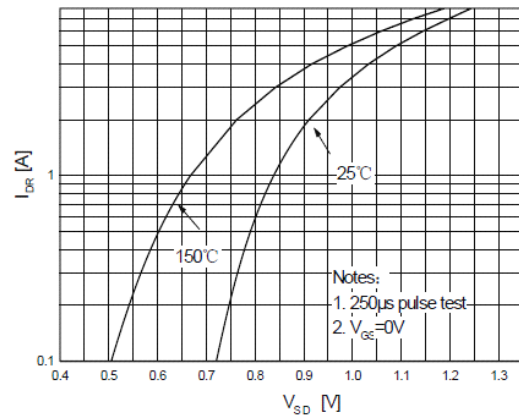
**Fig. 1 On-State Characteristics**



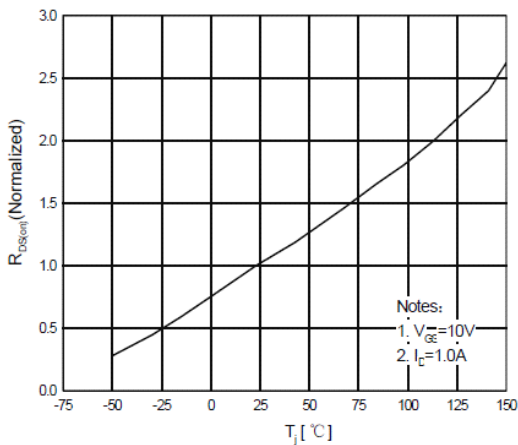
**Fig. 2 Transfer Current Characteristics**



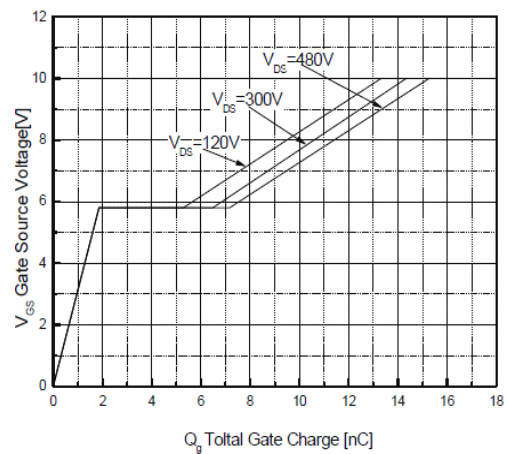
**Fig. 3 On-Resistance Variation vs Drain Current**



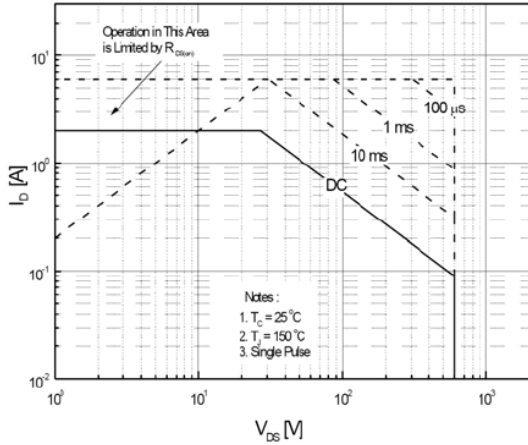
**Fig. 4 Body Diode Forward Voltage Variation vs. Source Current and Temperature**



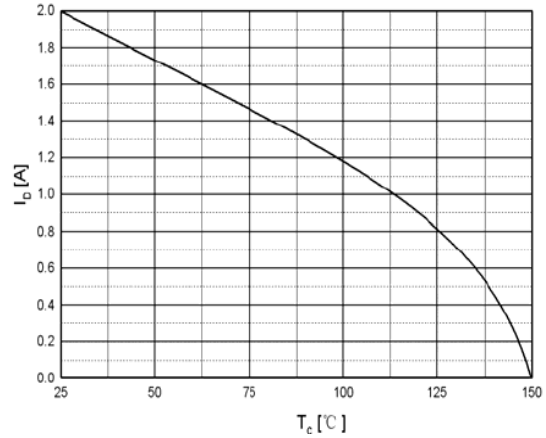
**Fig. 5 On-Resistance Variation vs Junction Temperature**



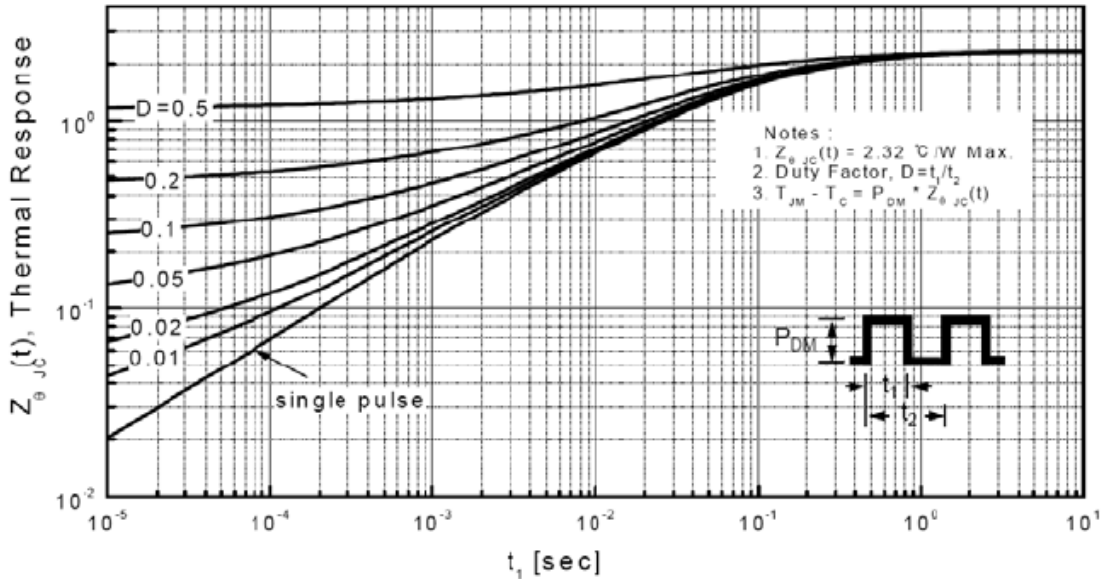
**Fig. 6 Gate Charge Characteristics**



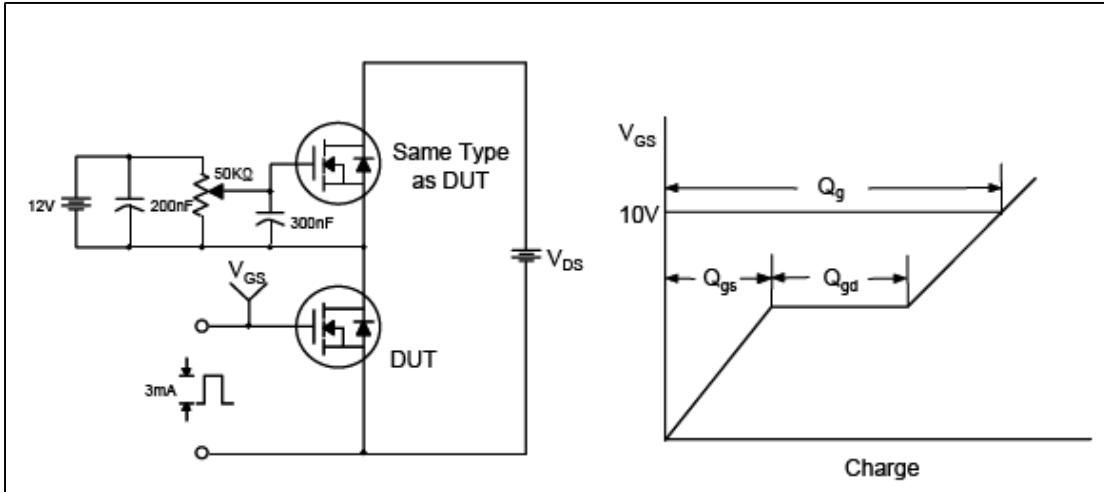
**Fig.7 Maximum Safe Operation Area**



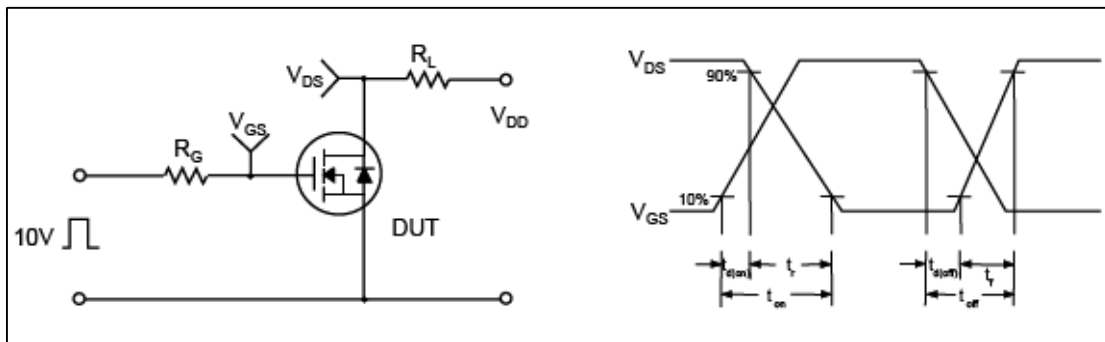
**Fig.8 Maximum Drain Current vs Case Temperature**



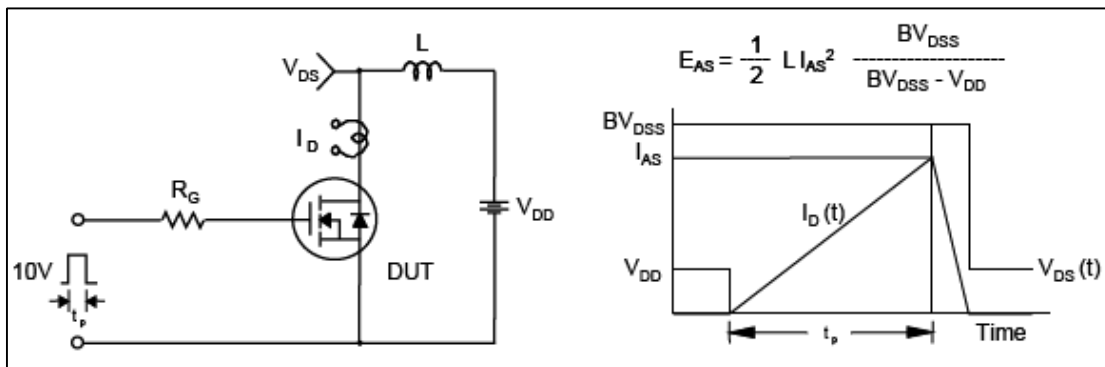
**Fig.9 Transient Thermal Response Curve**



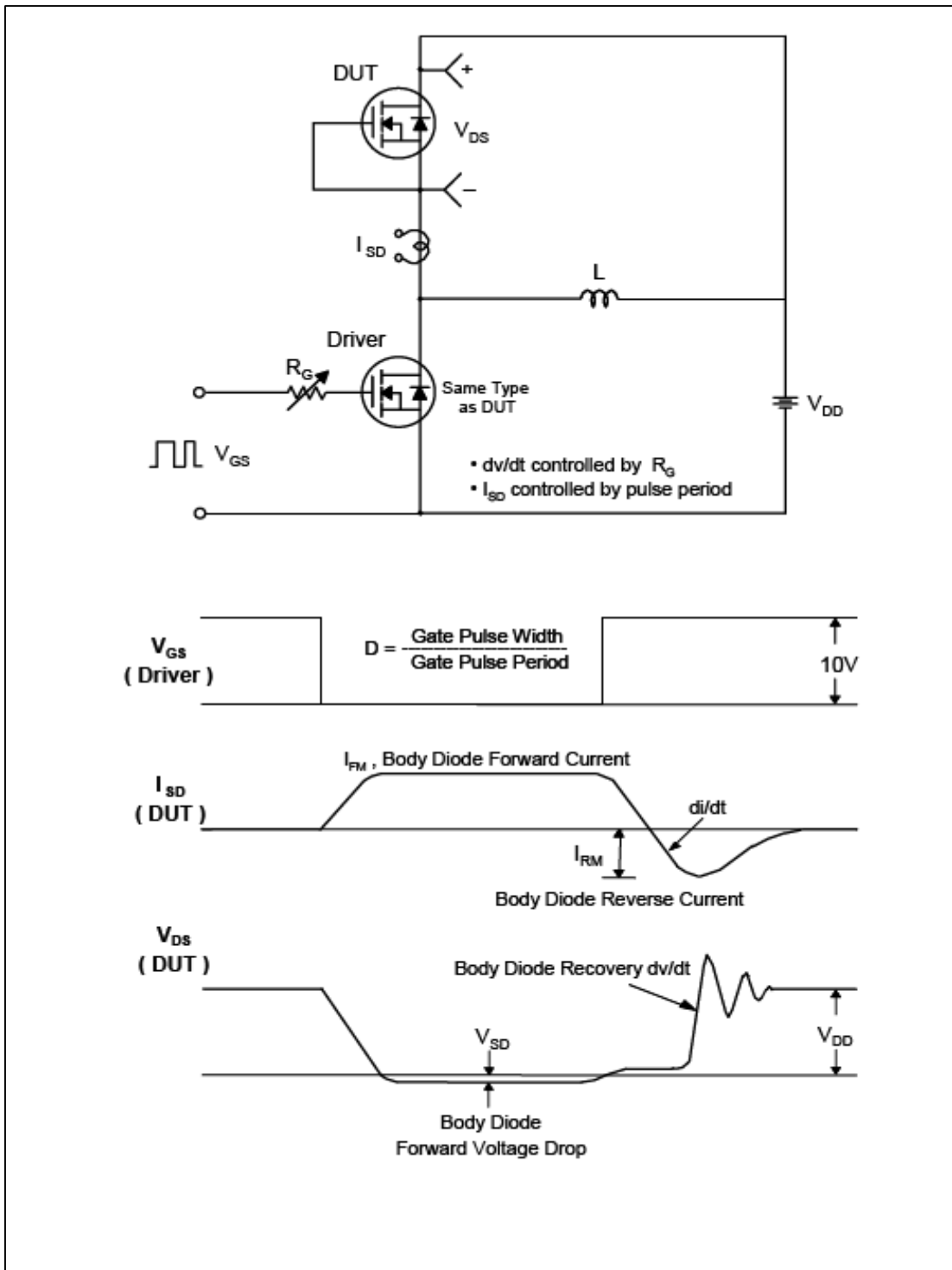
**Fig.10 Gate Test Circuit & Waveform**



**Fig.11 Resistive Switching Test Circuit & Waveform**



**Fig.12 Unclamped Inductive Switching Test Circuit & Waveform**



**Fig.13 Peak Diode Recovery  $dv/dt$  Test Circuit & Waveform**

**TO-220 Package Dimension**

